

PATENT APPLICATION

Sheet 1 of 2

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO.
	10020182-2	10780054
	APPLICANT	
	Vahé Adamian	
FILING DATE	GROUP	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	*	DOCUMENT NUMBER	DATE	NAME
<i>an</i>	*	US20030135344	Jul 17, 2003	Martens
	*	6,300,775	10-2001	Peach et al.
	*	US20030173978	Sept 18, 2003	Adamian et al.
	*	5,025,402	Jun 18, 1991	Winkelstein
	*	US20030200039	Oct 23, 2003	Adamian et al.
	*	5,548,221	Aug 20, 1996	Adamian et al.
	*	6,106,563	Aug 22, 2000	Stengel et al.
	*	5,793,213	08-1998	Bockelman et al.
	*	5,537,046	07-1996	Adamian et al.
<i>an</i>	*	6,539,344	03-2003	Stengel et al.

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>an</i>	*	Agilent Technologies, Inc. Application Note entitled "De-embedding and Embedding S-Parameter Networks Using a Vector Network Analyzer", March 22, 2001
<i>an</i>	*	Bockelman and Eisenstadt, "Combined Differential and Common Mode Scattering Parameters: Theory and Simulation", IEEE Transactions on Microwave Theory and Techniques, Vol. 43, No. 7, July 1995
<i>an</i>	*	Bockelman, Eisenstadt, and Stengel, "Accuracy Estimation of Mixed Mode Scattering Parameter Measurements", IEEE Transactions on Microwave Theory and Techniques, Vol. 47, No. 1, January 1999

EXAMINER

DATE CONSIDERED

*Timmy Nguyen**12/22/04*

* Copies of these references are not enclosed pursuant to 37 CFR 1.98(d). (See accompanying IDS)

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EXAMINER INITIAL	*	DOCUMENT NUMBER	DATE	NAME
<i>AV</i>	*	US20020053899	May 9, 2002	Adamian et al.
<i>AV</i>	*	5,578,932	11/26/96	Adamian et al.
<i>AV</i>	*	5,434,511	7/18/95	Adamian et al.

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	TRANSLATION	
					YES	NO

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

<i>AV</i>	*	Bockelman and Eisenstadt, "Calibration and Verification of the Pure Mode Vector Network Analyzer", IEEE Transactions on Microwav Theory and Techniques, Vol. 46, No. 7, July 1998
<i>AV</i>	*	Bockelman, Eisenstadt and Stengel, "Pure Mode Network Analyzer for On-Wafer Measurements of Mixed-Mode S-Parameters of Differential Circuits", "IEEE Transactions on Microwave Theory and Techniques, Vol. 45, No. 7, July 1997

EXAMINER <i>Jimmy Nguyen</i>	DATE CONSIDERED <i>12/22/04</i>
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